

FORM PTO-1449/A and its (Modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT				APPLICATION NO.: 10/019,589	ATTY. DOCKET NO.: T0529.70038US00
				FILING DATE: December 20, 2001	CONFIRMATION NO.: 1695
				APPLICANT: Roger Faulkner	
				GROUP ART UNIT: 2643	EXAMINER: Tran, Q.D.
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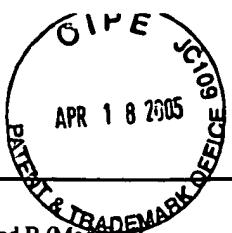
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